

<b>Notice of References Cited</b>	Application/Control No. 10/766,710		Applicant(s)/Patent Under Reexamination LEE, HEON	
	Examiner Kin-Chan Chen		Art Unit 1765	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0161431	07-2005	Lee, Heon	216/054
*	B	US-2004/0266064	12-2004	Davison, Peter A.	438/120
*	C	US-2004/0211754	10-2004	Sreenivasan, Sidlgata V.	216/041
*	D	US-6,755,984	06-2004	Lee et al.	216/54
*	E	US-6,671,034	12-2003	Hatakeyama et al.	355/67
*	F	US-2003/0205657	11-2003	Voisin, Ronald D.	249/187.1
*	G	US-2003/0141276	07-2003	Lee, Heon	216/8
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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